

Usage Fees – NIMS Users

2023.4.1

Equipment	Support Type 1.Common Use 2.Technical Support 3.Technical Surrogate 4.Collaborative Research	Billing Unit for Common Use and Technical Support (Technical Surrogate=0.25h)	Usage Fees (yen/1 hour) tax included				
			Common Use	Technical Support	Technical Surrogate1	Technical Surrogate2	Technical Surrogate3
Real working environment physical characterization TEM JEM-ARM200F-G	1,2,3,4	Session(3.5h)	6,600	9,075	9,322	11,550	14,025
Real working environmental electron holography microscope JEM-ARM200F-B	1,2,3,4	Session(3.5h)	6,600	9,075	9,322	11,550	14,025
200kV field emission transmission electron microscope JEM-2100F1, JEM-2100F2	1,2,3,4	Session(3.5h)	3,300	5,775	6,022	8,250	10,725
200kV transmission electron microscope JEM-2100	1,2,3,4	Session(3.5h)	1,650	4,125	4,372	6,600	9,075
Double-tilt bias and heating TEM holder Lightning	1,2,3,4	Session(3.5h)	1,650	4,125	4,372	6,600	9,075
Double-tilt LN2 cryo TEM holder Gatan 636	1,2,3,4	Session(3.5h)	1,650	4,125	4,372	6,600	9,075
Field emission scanning electron microscope JSM-7000F	1,2,3,4	Session(3.5h)	—	—	4,372	6,600	9,075
Dual Beam system NB5000	1,2,3,4	Session(3.5h)	4,950	7,425	7,672	9,900	12,375
FIB/SEM microfabrication instrument Helios 650	1,2,3,4	Session(3.5h)	3,300	5,775	6,022	8,250	10,725
Focused Ion Beam systems JIB-4000, JEM-9320FIB	1,2,3,4	Session(3.5h)	1,650	4,125	4,372	6,600	9,075
Focused Ion Beam systems Pick-up System	1,2,3,4	0.25h	1,650	4,125	4,372	6,600	9,075
Ultramicrotome Leica EM UC6	1,2,3,4	1h	1,650	4,125	4,372	6,600	9,075
HRTEM Analysis system	2,3,4	1h	—	4,125	4,372	6,600	9,075
Electron tomography analysis system	2,3,4	1h	—	4,125	4,372	6,600	9,075
DPC analysis system	2,3,4	1h	—	4,125	4,372	6,600	9,075
TEM sample preparation apparatus	1,2,3,4	Common Use=1h Technical Support=0.25h	1,650	4,125	4,372	6,600	9,075

※The setting of the fee for "Technical Surrogate" is divided into 3 types according to the difficulty level.
The level 2 applies to standard operations.